## **PATENT**

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent No.:

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Issue Date:

05/03/2005

5 App. No.:

10/707,080

Filing Date:

11/20/2003

Inventors:

Ching-Sung Yang et al.

Examiner:

Jerome Jackson

Art Unit:

2815

Docket No.:

EMEP0029USA4

10 Title: EEPROM WITH SOURCE LINE VOLTAGE STABILIZATION

MECHANISM

To:

Commissioner for Patents

P.O. BOX 1450

Alexandria, VA 22313-1450

15

Subject:

Request for Certificate of Correction under 37 CFR 1.322

Dear Sir,

Upon reviewing the above-identified patent, patentee noted the status of the parent application of above-identified patent should be corrected. The parent application has been patented on 01/25/2005 (see Attachment, the front page of the Patent No. 6,847,087) and it indicates this as an Office mistake of consequence. As the agent of record, I hereby request that a Certificate of Correction be issued under 37 CFR 1.322 to correct the status of the parent application from "abandoned" to "patented".

Respectfully submitted,

Wenton Lan

Data: JUL 1 5 2005

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# (12) United States Patent

Yang et al.

(10) Patent No.:

US 6,888,190 B2

(45) Date of Patent:

May 3, 2005

# (54) EEPROM WITH SOURCE LINE VOLTAGE STABILIZATION MECHANISM

- (75) Inventors: Ching-Sung Yang, Hsin-Chu (TW); Shih-Jye Shen, Hsin-Chu (TW); Ching-Hsiang Hsu, Hsin-Chu (TW)
- (73) Assignce: eMemory Technology Inc., Hsin-Chu (TW)
- (\*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35

U.S.C. 154(b) by 0 days.

- (21) Appl. No.: 10/707,080
- (22) Filed: Nov. 20, 2003
- (65) Prior Publication Data

US 2004/0099914 A1 May 27, 2004

#### Related U.S. Application Data

- (63) Continuation-in-part of application No. 10/065,591, filed on Oct. 31, 2002, now abandoned.
- (51) Int. Cl.<sup>7</sup> ...... H01L 29/76; H01L 29/78; H01L 29/788

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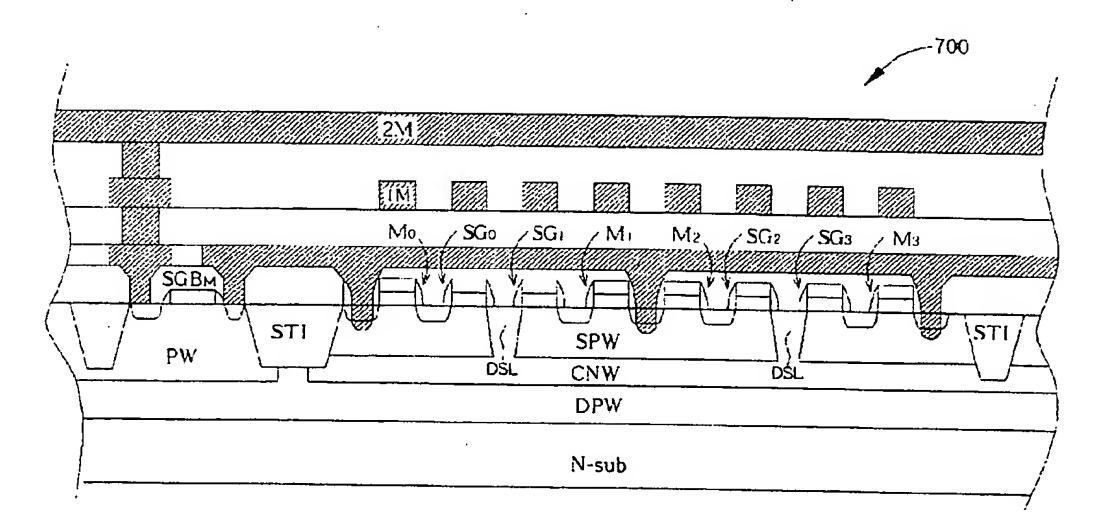
<sup>\*</sup> cited by examiner

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#### (57) ABSTRACT

A low-voltage nonvolatile memory array includes an N type semiconductor substrate having a memory region. A deep P well is formed in the semiconductor substrate. A cell N well is located within the memory region in the semiconductor substrate. The cell N well is situated above the deep ion well. A shallow P well serving as a buried bit line is doped within the cell ion well. The shallow P well is isolated by an STI layer, wherein the STI layer has a thickness greater than a well depth of the shallow ion well. At least one memory transistor with a stacked gate, a source, and a drain is formed on the shallow ion well. The source of the memory transistor is electrically coupled to the cell N well to induce a capacitor between the cell N well and the deep P well during a read operation, thereby avoiding read current bounce or potential power crash. A bit line overlies the memory transistor and is electrically connected to the drain of the memory transistor via a bit line contact plug short-circuiting the drain of the memory transistor and the shallow P well.

#### 15 Claims, 29 Drawing Sheets



## (12) United States Patent Yang et al.

(10) Patent No.:

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(45) Date of Patent:

\*Jan. 25, 2005

#### (54) BI-DIRECTIONAL FOWLER-NORDHEIM TUNNELING FLASH MEMORY

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Assignee: eMemory Technology Inc., Hsin Chu

(TW)

Subject to any disclaimer, the term of this (\*) Notice: patent is extended or adjusted under 35 U.S.C. 154(b) by 175 days.

This patent is subject to a terminal disclaimer.

Appl. No.: 10/065,591 (21)

Oct. 31, 2002 (22)Filed:

**Prior Publication Data** (65)

US 2004/0252541 A1 Dec. 16, 2004

(51) Int. Cl.<sup>7</sup> ...... H01L 29/76; H01L 29/94; H01L 31/062; H01L 31/113; H01L 31/119

257/318; 257/390

Field of Search ...... 257/208, 314-316, 257/318, 319, 322, 390, 391

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(57) **ABSTRACT** 

A low-voltage nonvolatile memory array includes a cell well of a first conductivity type formed in a substrate; columns of buried bit lines of a second conductivity type formed within the cell well, wherein columns of the buried bit lines are isolated from each other and each is further divided into of sub-bit line segments with deeply doped source wells of the first conductivity type connected to the cell well; a plurality of memory cell blocks serially arranged over one of the columns of buried bit lines, wherein a memory cell block corresponds to a sub-bit line segment, and each memory cell block includes at least one memory transistor having a stacked gate, source, and drain; and a local bit line overlying the memory cell blocks and electrically connected to the drain of the memory transistor via a contact plug shortcircuiting the drain and the subjacent buried bit line.

### 21 Claims, 24 Drawing Sheets

